IN THE CLAIMS

All currently pending claims and status indicators are set forth below: 1-13. (Canceled)

- 14. (Original) A method of simultaneously accessing a plurality of memory array blocks in a synchronous random access memory (SRAM) device, comprising the acts of:
 - receiving a first signal at a first input of a logical device, the first signal corresponding to a memory array block selection signal;
 - receiving a second signal at a second input of the logical device, the second signal corresponding to a testmode enable signal;
 - producing an output signal from the logical device, wherein the output signal corresponds to one of the first signal and the second signal;
 - enabling a plurality of memory array block select lines in response to the output signal from the logical device; and
 - writing data to a plurality of memory array blocks corresponding to the enabled memory array block select lines.
- 15. (Original) The method of simultaneously accessing a plurality of memory array blocks in a synchronous random access memory (SRAM) device, as set forth in claim 14, wherein the acts of receiving comprise receiving the first signal and the second signal at a NAND gate.
- 16. (Original) The method of simultaneously accessing a plurality of memory array blocks in a synchronous random access memory (SRAM) device, as set forth in claim 14, comprising:

producing an output signal from the logical device, wherein the output signal corresponds to the testmode enable signal;

enabling a plurality of memory array block select lines in response to the output signal, each of the plurality of memory array block select lines corresponding to one of a plurality of memory array blocks; and writing data to the plurality of memory array blocks.

17-21. (Canceled)

- 22. (Previously presented) A method of programming/burning-in on SRAM comprises: selecting a plurality of memory array blocks in the SRAM; and simultaneously writing to each of the plurality of memory array blocks during burn-in testing.
- 23. (Previously presented) The method, as set forth in claim 22, wherein selecting comprises:

providing a block selection signal and a testmode signal to a logical device.

24. (Previously presented) The method, as set forth in claim 22, wherein selecting comprises:

providing a clock selection signal and a testmode signal to a NAND gate.

25. (Previously presented) The method, as set forth in claim 22, wherein simultaneously writing comprises transmitting data to a plurality of local write drivers.

- 26. (Previously presented) The method, as set forth in claim 25, comprising driving the data from each of the plurality of local write drivers to a respective one of the plurality of memory array blocks.
 - 27. (Previously presented) A method of programming/burning-in an SRAM: combining a plurality of signals produced externally with respect to the SRAM; producing an internal signal configured to simultaneously select a plurality of memory array blocks in the SRAM; and simultaneously writing to each of the plurality of memory array blocks.
- 28. (Previously presented) The method, as set forth in claim 27, wherein combining comprises combining the plurality of signals through a logical device located internally with respect to the SRAM.
- 29. (Previously presented) The method, as set forth in claim 28, wherein producing comprises producing an internal signal from an output of the logical device.
- 30. (Previously presented) The method, as set forth in claim 27, wherein combining comprises combining the plurality of signals through a logical device located internally with respect to the NAND gate.

- 31. (Previously presented) The method, as set forth in claim 27, wherein simultaneously writing comprises simultaneously writing to each of the plurality of memory array blocks during burn-in.
- 32. (Previously presented) The method, as set forth in claim 27, wherein simultaneously writing comprises transmitting data to a plurality of local write drivers.
- 33. (Previously presented) The method, as set forth in claim 32, comprising driving the data from each of the plurality of local write drivers to a respective one of the plurality of memory array blocks.